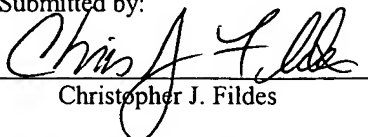
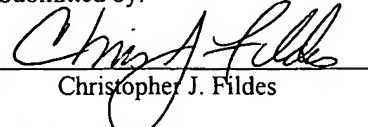


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Registration No. 32,132				APPLICANT Ismo Kallio et al.			
				FILING DATE		GROUP ART UNIT	
U.S. PATENT DOCUMENTS							
EXAMINER INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
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	AF						
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	AI						
	AJ						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
	AK	83402		FI			
	AL	69145		FI			
	AM	108738		FI			
	AN	84508		FI			
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
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<b>APPLICANT</b> Ismo Kallio et al.				<b>FILING DATE</b> 			
<b>GROUP ART UNIT</b> 							

U.S. PATENT DOCUMENTS							
EXAMINER INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
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	AG						
	AH						
	AI						
	AJ						

FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
	AK	4362		FI			
	AL	10115618		DE			
	AM	00/19013		WO			
	AN						

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)	
	AO
	AP
	AQ

<b>EXAMINER</b> 	<b>DATE CONSIDERED</b> 
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<b>PATENTTIHAKEMUS NRO</b>	<b>LUOKITUS</b>
20021844	D21G 1/00, 9/00

<b>TUTKITTU AINEISTO</b>
Patenttijulkaisukokoelma (FI, SE, NO, DK, DE, CH, EP, WO, GB, US), tutkitut luokat D21G, D21F
Tiedonhaut ja muu aineisto EPODOC, WPI, PAJ

<b>VIITEJULKAISUT</b>		
<b>Kategoria*)</b>	<b>Julkaisun tunnistetiedot</b>	<b>Koskee vaatimuksia</b>
A	FI 83402 B (B26D 1/30)	
A	FI 69145 B (D 21 F 7/00)	
A	FI 108738 B (D21F 7/00)	
A	FI 84508 B (D21F 7/00)	
A	FI 4362 U (D21G 1/00)	
A	DE 10115618 A1 (D21F 2/00)	
A	WO 00/19013 (D21F 7/00)	
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